

October 2009
UniFETTM

FDP16N50U / FDPF16N50UT N-Channel MOSFET, FRFET 500V, 15A, 0.48 Ω

Features

- $R_{DS(on)} = 0.37\Omega$ (Typ.)@ $V_{GS} = 10V$, $I_D = 7.5A$
- Low gate charge (Typ. 32nC)
- Low C_{rss} (Typ. 20pF)
- · Fast switching
- 100% avalanche tested
- · Improved dv/dt capability
- · RoHS compliant



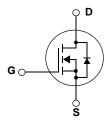
Description

These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advance technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficient switching mode power supplies and active power factor correction.







MOSFET Maximum Ratings T_C = 25°C unless otherwise noted*

Symbol		Parameter		FDP16N50U	FDPF16N50UT	Units	
V_{DSS}	Drain to Source Voltage	rain to Source Voltage			500		
V _{GSS}	Gate to Source Voltage	Gate to Source Voltage			:30	V	
	Drain Current -Continuous (T _C = 25°C)			15	15*	^	
ID	Drain Current	-Continuous (T _C = 100°C)		9	9*	Α	
I _{DM}	Drain Current	- Pulsed	(Note 1)	60	60*	Α	
E _{AS}	Single Pulsed Avalanche Energy (Note			2) 610		mJ	
I _{AR}	Avalanche Current	(Note 1)) 15		Α		
E _{AR}	Repetitive Avalanche Ene	Repetitive Avalanche Energy			20	mJ	
dv/dt	Peak Diode Recovery dv/d	dt	(Note 3)) 20		V/ns	
D	Dawar Dissination	$(T_C = 25^{\circ}C)$		200	38.5	W	
P_{D}	Power Dissipation	- Derate above 25°C		1.59	0.3	W/ºC	
T _J , T _{STG}	Operating and Storage Te	Operating and Storage Temperature Range			o +150	οС	
T _L	•	Maximum Lead Temperature for Soldering Purpose, 1/8" from Case for 5 Seconds			800	°C	

*Drain current limited by maximum junction temperature

Thermal Characteristics

Symbol	Parameter	FDP16N50U	FDPF16N50UT	Units
$R_{\theta JC}$	Thermal Resistance, Junction to Case	ermal Resistance, Junction to Case 0.63 3.3		
$R_{\theta CS}$	Thermal Resistance, Junction to Ambient 0.5 -		-	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	62.5	62.5	

Package Marking and Ordering Information $T_C = 25^{\circ}C$ unless otherwise noted

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDP16N50U	FDP16N50U	TO-220	-	-	50
FDPF16N50UT	FDPF16N50UT	TO-220F	-	-	50

Electrical Characteristics

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Units
Off Charac	cteristics					
BV _{DSS}	Drain to Source Breakdown Voltage	$I_D = 250\mu A, V_{GS} = 0V, T_J = 25^{\circ}C$	500	-	-	V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	I _D = 250μA, Referenced to 25°C	-	0.5	-	V/°C
	Zero Gate Voltage Drain Current	$V_{DS} = 500V, V_{GS} = 0V$	-	-	25	
IDSS	Zero Gate Voltage Drain Current	$V_{DS} = 400V, T_{C} = 125^{\circ}C$	-	-	250	μΑ
I _{GSS}	Gate to Body Leakage Current	$V_{GS} = \pm 30V, V_{DS} = 0V$	-	-	±100	nA

On Characteristics

V _{GS(th)}	Gate Threshold Voltage	$V_{GS} = V_{DS}$, $I_D = 250\mu A$	3.0	-	5.0	V
R _{DS(on)}	Static Drain to Source On Resistance	$V_{GS} = 10V, I_D = 7.5A$	-	0.37	0.48	Ω
9 _{FS}	Forward Transconductance	$V_{DS} = 40V, I_D = 7.5A$ (Note 4)	=	23	-	S

Dynamic Characteristics

C _{iss}	Input Capacitance	V _{DS} = 25V, V _{GS} = 0V f = 1MHz		=	1495	1945	pF
C _{oss}	Output Capacitance			-	235	310	pF
C _{rss}	Reverse Transfer Capacitance	1 - 11/11/12		-	20	30	pF
$Q_{g(tot)}$	Total Gate Charge at 10V			-	32	45	nC
Q_{gs}	Gate to Source Gate Charge	$V_{DS} = 400V, I_{D} = 15A$		-	8.5	-	nC
Q_{gd}	Gate to Drain "Miller" Charge	V _{GS} = 10V	(Note 4, 5)	-	14	-	nC

Switching Characteristics

t _{d(on)}	Turn-On Delay Time		-	40	90	ns
t _r	Turn-On Rise Time	$V_{DD} = 250V, I_D = 15A$	-	150	310	ns
t _{d(off)}	Turn-Off Delay Time	$R_G = 25\Omega$	-	65	140	ns
t _f	Turn-Off Fall Time	(Note 4, 5)	-	80	170	ns

Drain-Source Diode Characteristics

I _S	Maximum Continuous Drain to Source Diode Forward Current			-	-	15	Α
I _{SM}	Maximum Pulsed Drain to Source Diode Forward Current			-	-	60	Α
V_{SD}	Drain to Source Diode Forward Voltage	V _{GS} = 0V, I _{SD} = 15A		-	-	1.6	V
t _{rr}	Reverse Recovery Time	V _{GS} = 0V, I _{SD} = 15A		-	65	-	ns
Q _{rr}	Reverse Recovery Charge	$dI_F/dt = 100A/\mu s (N$	Note 4)	-	0.1	-	μС

- Repetitive Rating: Pulse width limited by maximum junction temperature
- 2. L = 5.5mH, I $_{AS}$ = 15A, V $_{DD}$ = 50V, R $_{G}$ = 25 $\!\Omega$, Starting T $_{J}$ = 25°C
- 3. $I_{SD} \le 16 A$, di/dt $\le 200 A/\mu s$, $V_{DD} \le BV_{DSS}$, Starting $T_J = 25^{\circ}C$
- 4. Pulse Test: Pulse width $\leq 300 \mu s, \, Duty \, Cycle \leq 2\%$
- 5. Essentially Independent of Operating Temperature Typical Characteristics

Typical Performance Characteristics

Figure 1. On-Region Characteristics

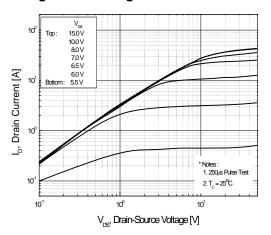


Figure 3. On-Resistance Variation vs.

Drain Current and Gate Voltage

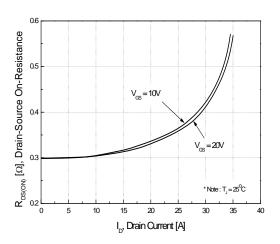


Figure 5. Capacitance Characteristics

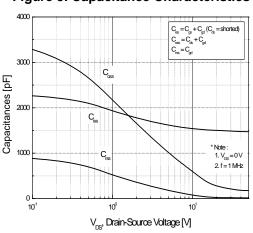


Figure 2. Transfer Characteristics

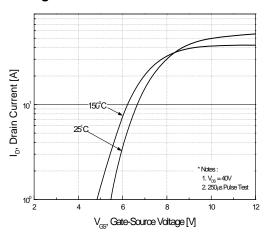


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

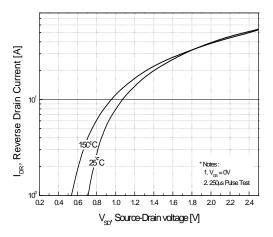
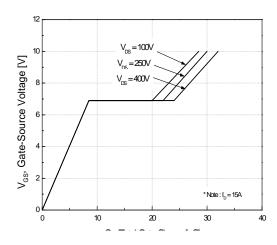


Figure 6. Gate Charge Characteristics



Typical Performance Characteristics (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

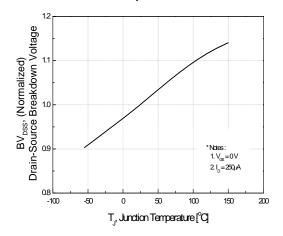


Figure 8. Maximum Safe Operating Area - FDPF16N50UT

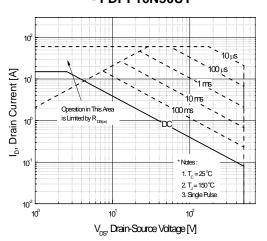


Figure 9. Maximum Drain Current vs. Case Temperature - FDPF16N50UT

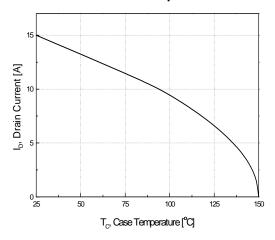
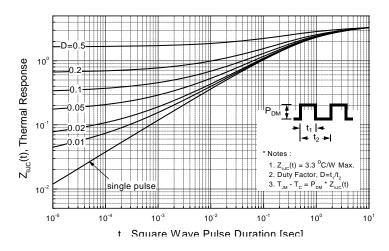
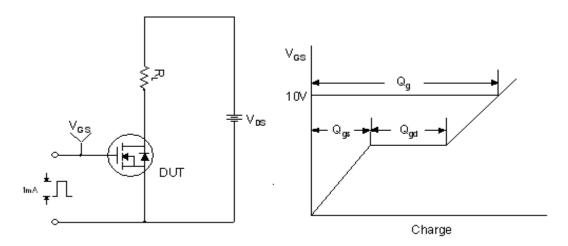


Figure 10. Transient Thermal Response Curve - FDPF16N50UT

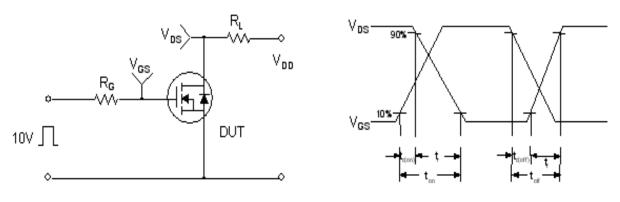


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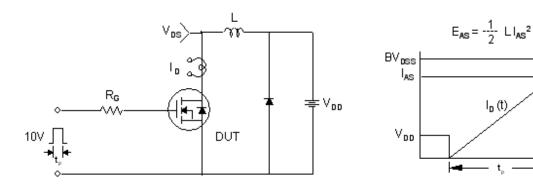
Gate Charge Test Circuit & Waveform



Resistive Switching Test Circuit & Waveforms

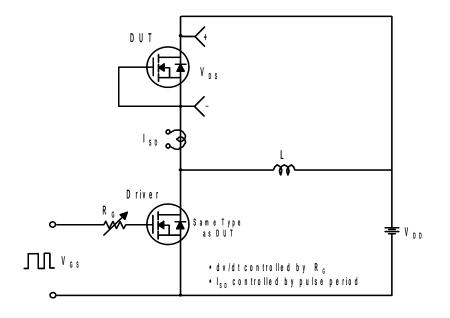


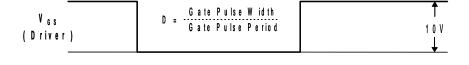
Unclamped Inductive Switching Test Circuit & Waveforms

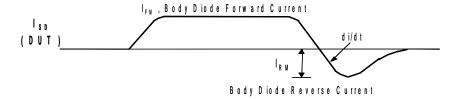


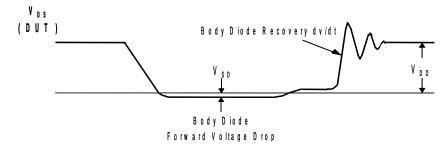
V_{os} (t)

Peak Diode Recovery dv/dt Test Circuit & Waveforms



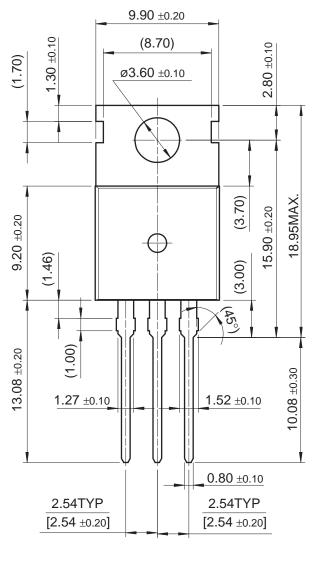


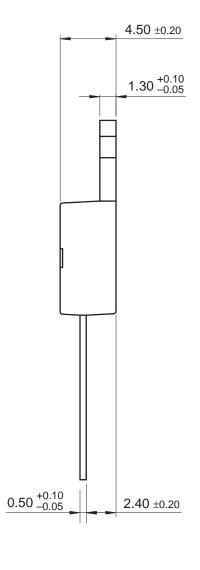




Mechanical Dimensions

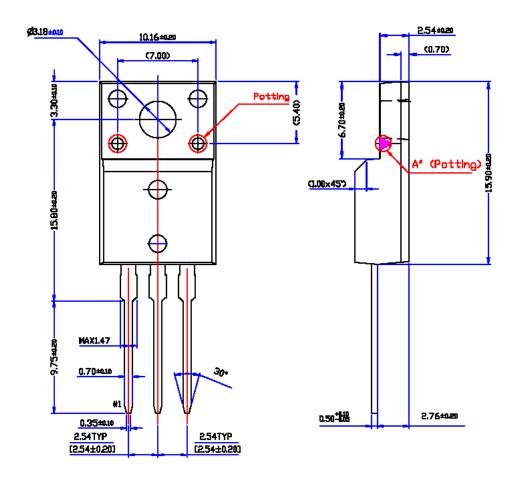
TO-220

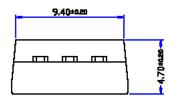




Package Dimensions

TO-220F Potted





* Front/Back Side Isolation Voltage : AC2500V

Dimensions in Millimeters





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